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Application/Control No.	Applicant(s)/Patent under Reexamination
10/810,964	DEY ET AL.
Examiner	Art Unit
Chau Nguyen	2176

SEARCHED			
Class	Subclass	Date	Examiner
715	501.1	4/3/2006	CN
707	4	4/3/2006	CN
707	6	4/3/2006	CN
707	101	4/3/2006	CN
707	102	4/3/2006	CN
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH)_
	DATE	EXMR
East Reports	4/3/2006	CN-
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Inventor Search	4/3/2006	CN